

	Application/Control No.	Applicant(s)/Patent under Reexamination	
	09/494,514	NAVEEN ET AL.	
Ì	Examiner	Art Unit	
	Michael W. Bowen	2625	

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Class	Subclass	Date	Examiner			
382	305 partial search	7/5/05	MWB			
707	1-7, 104.1 partial	7/06/05	MWB			
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INTERFERENCE SEARCHED					
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Class & text search US PAT, US PG-PUB 345/418-475, 581-689 348/445, 556, 571-721, 844, 913 382/108, 155-231, 254-308, 325 706/934 707/1-7, 104.1	6/26/05	MWB				
Search backward citation of US PAT 6,882,746 Naveen Note related application 09/495642	1/5/05	MWB				
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